Supplementary information for

Boosting up phonon-induced luminescence in red fluoride phosphors via composition variation driven structural transformations

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Rietveld structural refinement on powder XRD pattern



Figure S1 Measured and calculated XRD patterns on K₂SiF₆:Mn⁴⁺ phosphor.



Figure S2 Measured and calculated XRD patterns on (K_{0.75}Na_{0.25})₂SiF₆:Mn⁴⁺ phosphor.



Figure S3 Measured and calculated XRD patterns on $KNaSiF_6:Mn^{4+}$ phosphor.



Figure S4 Measured and calculated XRD patterns on $(K_{0.25}Na_{0.75})_2SiF_6:Mn^{4+}$ phosphor.



Figure S5 Measured and calculated XRD patterns on Na₂SiF₆:Mn⁴⁺ phosphor.

Samples	Rwp	Rp	Reduced χ ²
K ₂ SiF ₆ :Mn ⁴⁺	0.1161	0.0885	2.695
$(K_{0.75}Na_{0.25})_2SiF_6:Mn^{4+}$	0.1039	0.0789	1.915
KNaSiF ₆ :Mn ⁴⁺	0.1298	0.0900	4.742
$(K_{0.25}Na_{0.75})_2SiF_6:Mn^{4+}$	0.0968	0.0737	2.367
Na ₂ SiF ₆ :Mn ⁴⁺	0.0985	0.0750	2.835

Table S1. Rietveld structural refinement results for each phosphor.